

AUTOMOTIVE GRADE

HEXFET® Power MOSFET

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching

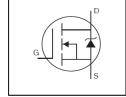
Description

• Repetitive Avalanche Allowed up to Tjmax

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature,

fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide

- · Lead-Free, RoHS Compliant
- Automotive Qualified *



V _{DSS}	40V
R _{DS(on)} max.	3.7mΩ
D (Silicon Limited)	180A ●
D (Package Limited)	160A

ren gos





TO-220AB AUIRF1404Z

D²Pak AUIRF1404ZS

AUIRF1404ZL

G	D	S
Gate	Drain	Source

Decement number	Doolsono Tyro	Standard Paci	(Orderable Port Number	
Base part number	Package Type	Form	Quantity	Orderable Part Number	
AUIRF1404Z	TO-220	Tube	50	AUIRF1404Z	
AUIRF1404ZL	TO-262	Tube	50	AUIRF1404ZL	
AUIRF1404ZS	D ² -Pak	Tube	50	AUIRF1404ZS	
AUIRF 140425	D-Pak	Tape and Reel Left	800	AUIRF1404ZSTRL	

Absolute Maximum Ratings

variety of other applications.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units		
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	180❶			
$I_D @ T_C = 100^{\circ}C$	100°C Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) 120				
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	160	A		
I _{DM}	Pulsed Drain Current ①	710]		
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	200	W		
	Linear Derating Factor	1.3	W/°C		
V_{GS}	Gate-to-Source Voltage	± 20	V		
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	330	m l		
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ®	480	- mJ		
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α		
E _{AR}	Repetitive Avalanche Energy ©		mJ		
T_J	Operating Junction and	-55 to + 175			
T _{STG}	Storage Temperature Range		°C		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300]		
	Mounting torque, 6-32 or M3 screw ⑦	10 lbf•in (1.1N•m)			

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.759	
R _{eCS} Case-to-Sink, Flat, Greased Surface ⑦		0.50		0000
$R_{\theta JA}$			62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state) ®		40	

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.033		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		2.7	3.7	$m\Omega$	$V_{GS} = 10V, I_D = 75A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0	_	4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
gfs	Forward Trans conductance	170			S	$V_{DS} = 25V, I_{D} = 75A$
ı	Drain to Source Leakage Current			20		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125$ °C
	Gate-to-Source Forward Leakage			200	π Λ	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	<u>-</u>	 			
Q_g	Total Gate Charge	 100	150		$I_D = 75A$
Q_{gs}	Gate-to-Source Charge	 31		nC	$V_{DS} = 32V$
Q_{gd}	Gate-to-Drain Charge	 42			V _{GS} = 10V3
t _{d(on)}	Turn-On Delay Time	 18			$V_{DD} = 20V$
t _r	Rise Time	 110		ns	$I_D = 75A$
t _{d(off)}	Turn-Off Delay Time	 36		115	$R_G = 3.0\Omega$
t _f	Fall Time	 58			V _{GS} = 10V ③
L_D	Internal Drain Inductance	4.5			Between lead, 6mm (0.25in.)
Ls	Internal Source Inductance	 7.5			from package and center of die contact
C_{iss}	Input Capacitance	 4340			$V_{GS} = 0V$
C _{oss}	Output Capacitance	 1030			$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	 550			f = 1.0MHz
Coss	Output Capacitance	 3300		pF	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
Coss	Output Capacitance	 920			$V_{GS} = 0V$, $V_{DS} = 32V$ $f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 1350			$V_{GS} = 0V$, $V_{DS} = 0V$ to 32V \oplus

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			160		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			750	A	integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 75A, V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		28	42	ns	$T_J = 25^{\circ}C$, $I_F = 75A$, $V_{DD} = 20V$
Q_{rr}	Reverse Recovery Charge		34	51	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Limited by T_{Jmax} , starting $T_J = 25^{\circ}C$, L = 0.11mH, $R_G = 25\Omega$, $I_{AS} = 75$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.
- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- 6 This value determined from sample failure population, starting $T_J = 25^{\circ}C$, L = 0.11mH, $R_G = 25\Omega$, $I_{AS} = 75$ A, $V_{GS} = 10$ V.
- This is only applied to TO-220AB pakcage.
- This is applied to D²Pak When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- 9 TO-220 device will have an Rth value of 0.65°C/W.
- ® R_θ is measured at T_J approximately 90°C.
- Calculated continuous current based on maximum allowable junction temperature. Package limitation current limit is 160A.
 Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
 (Refer to AN-1140)



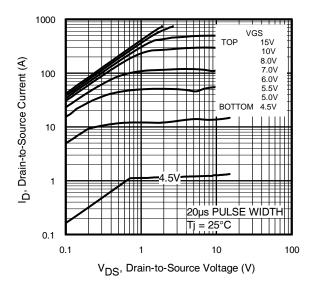


Fig. 1 Typical Output Characteristics

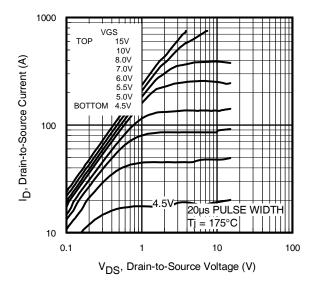


Fig. 2 Typical Output Characteristics

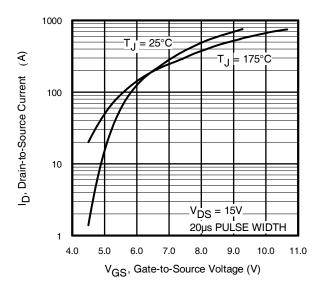


Fig. 3 Typical Transfer Characteristics

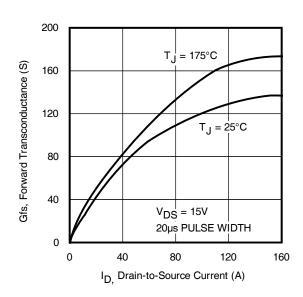


Fig. 4 Typical Forward Trans conductance vs. Drain Current



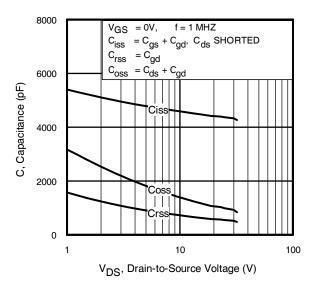


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

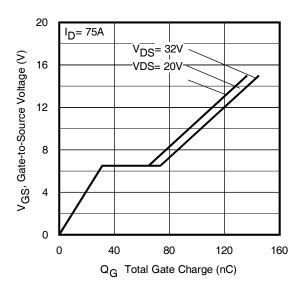


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

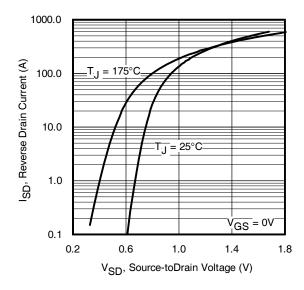


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

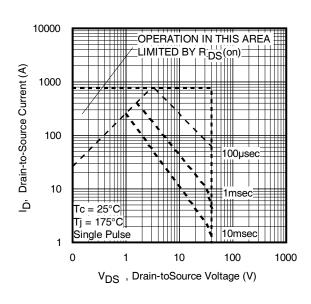
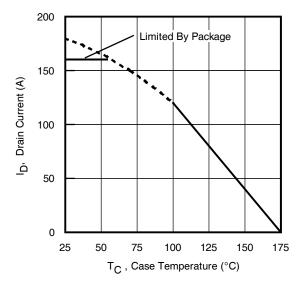


Fig 8. Maximum Safe Operating Area





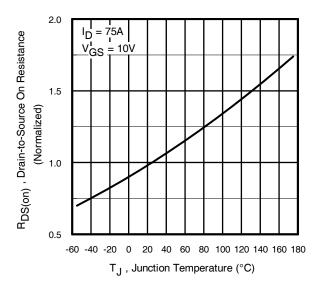


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance vs. Temperature

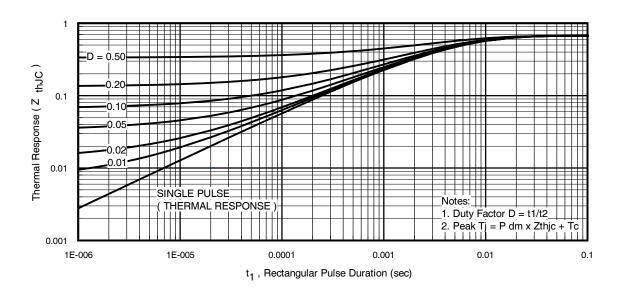


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



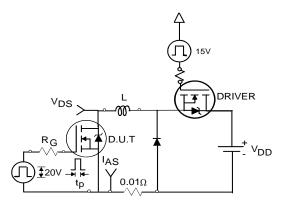


Fig 12a. Unclamped Inductive Test Circuit

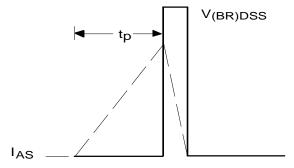


Fig 12b. Unclamped Inductive Waveforms

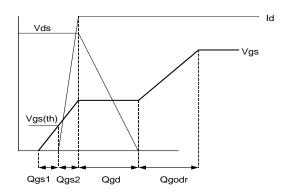


Fig 13a. Gate Charge Waveform

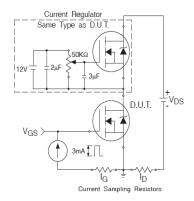


Fig 13b. Gate Charge Test Circuit

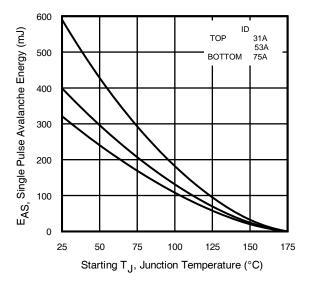


Fig 12c. Maximum Avalanche Energy vs. Drain Current

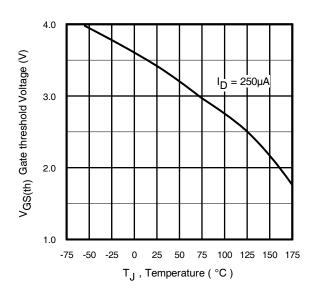


Fig 14. Threshold Voltage vs. Temperature



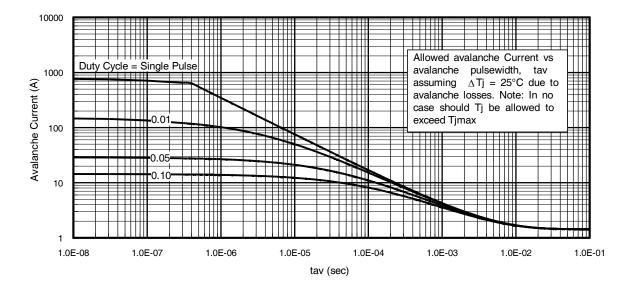


Fig 15. Typical Avalanche Current vs. Pulse width

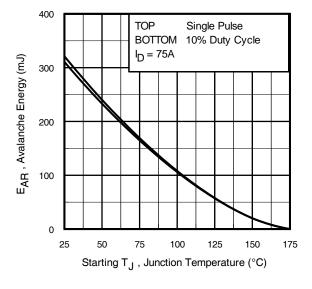


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

 $D = Duty cycle in avalanche = tav \cdot f$

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



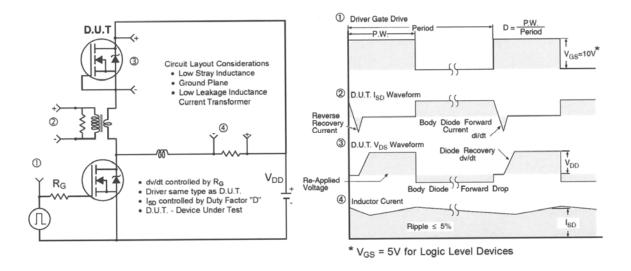


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

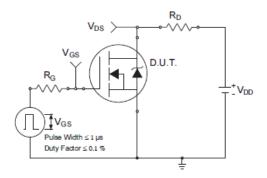


Fig 18a. Switching Time Test Circuit

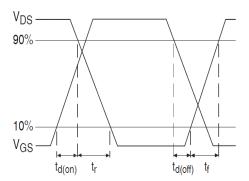
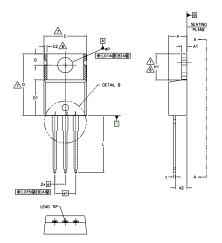
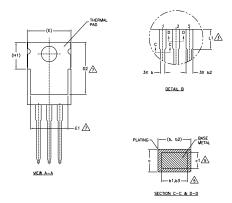


Fig 18b. Switching Time Waveforms



TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

- DIMENSIONING AND TOLERANGING AS PER ASMETTIS, 3M 1994.

 DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].

 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

 DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH

 SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4.83	.140	.190	
A1	1.14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.97	.015	.038	5
b2	1,14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
Ε	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	_	.030	8
е	2.54 BSC 5.08 BSC		.100	BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
øΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

LEAD ASSIGNMENTS

HEXFET

1.- GATE 2.- DRAIN 3.- SOURCE

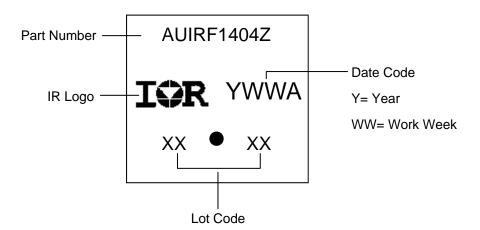
IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

- 1.- ANODE 2.- CATHODE 3.- ANODE

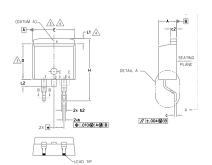
TO-220AB Part Marking Information

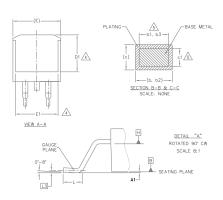


TO-220AB package is not recommended for Surface Mount Application.



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S		DIMENSIONS					
M B O	MILLIM	ETERS	INC	INCHES			
L	MIN.	MAX.	MIN.	MAX.	O T E S		
А	4.06	4.83	.160	.190			
A1	0.00	0.254	.000	.010			
Ь	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1.14	1.78	.045	.070			
ь3	1.14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
с1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	_	.270	_	4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	_	.245	_	4		
е	2.54	BSC	.100	BSC			
Н	14.61	15.88	.575	.625			
L	1.78	2.79	.070	.110			
L1	_	1.68	_	.066	4		
L2	_	1.78	_	.070			
L3	0.25 BSC		.010	BSC			

LEAD ASSIGNMENTS

DIODES

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

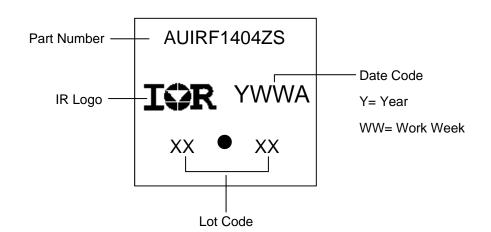
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

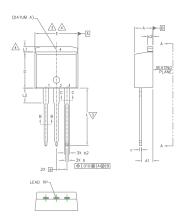
2, 4.- COLLECTOR 3.- EMITTER

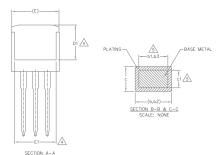
D²Pak (TO-263AB) Part Marking Information





TO-262 Package Outline (Dimensions are shown in millimeters (inches)





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3\DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

HEXFET

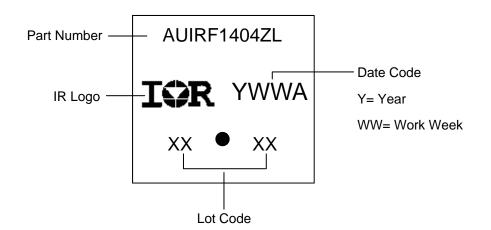
DIODES

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE 1.- GATE

2.- DRAIN 3.- SOURCE 4.- DRAIN

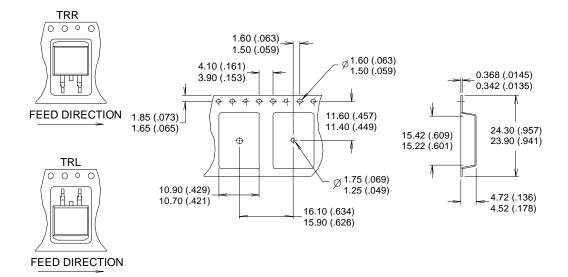
S Y M		DIMENSIONS					
В		MILLIM	ETERS		INCI	O T E S	
0 L		MIN.	MAX.		MIN.	MAX.	S
А		4.06	4.83		.160	.190	
A1		2.03	3.02		.080	.119	
b		0.51	0.99		.020	.039	
ь1		0.51	0.89		.020	.035	5
b2		1.14	1.78		.045	.070	
b3		1.14	1.73		.045	.068	5
С	-	D.38	0.74		.015	.029	
c1		0.38	0.58		.015	.023	5
c2		1.14	1.65		.045	.065	
D		8.38	9.65		.330	.380	3
D1		6.86	_		.270	_	4
E		9.65	10.67		.380	.420	3,4
E1		6.22	_		.245		4
е		2.54	BSC		.100	BSC	
L	1	3.46	14.10		.530	.555	
L1		_	1.65		_	.065	4
L2		3.56	3.71		.140	.146	

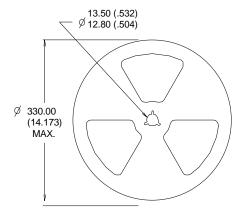
TO-262 Part Marking Information





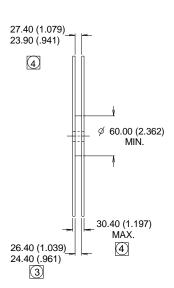
D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.





Qualification Information

			Automotivo				
		Automotive					
			(per AEC-Q101)				
Qualification Level			is part number(s) passed Automotive qualification. Infineon's consumer qualification level is granted by extension of the higher el.				
		TO-220AB	N/A				
Moisture	Moisture Sensitivity Level		MOL 4				
			MSL1				
	Machine Madel	Class M4 [†]					
	Machine Model	AEC-Q101-002					
ECD	Lluman Dady Madal	Class H1C [†]					
ESD	Human Body Model	AEC-Q101-001					
	Oleman I Davis a Martal	Class C3 [†]					
Charged Device Model		AEC-Q101-005					
RoHS Compliant		Yes					

[†] Highest passing voltage.

Revision History

Date	Comments
11/11/2015	Updated datasheet with corporate template
	Corrected ordering table on page 1.

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